Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination	
10807188	IKEDA ET AL.	
Examiner	Art Unit	
Chawan Sheela C	2624	

SEARCHED					
Class	Subclass	Date	Examiner		
382	145,242	1/7/07	SCC		
702	159	1/7/07	SCC		
249	16,102,104,140,16,35,55,99,193,192	1/7/07	SCC		
451	464,466,469,490	1/7/07	SCC		
700	182,187,	1/7/07	SCC		
264	225,254,256,35,34,338.33,316,259,255,245	1/7/07	SCC		
156	304.5	1/7/07	SCC		

SEARCH NOTES					
Search Notes	Date	Examiner			
EAST, US-PGPUB, USPAT, EPO, JPO, DERWENT, IBM-TDB.	1/7/07	SCC			
INVENTOR NAME SEARCH.	1/7/07	SCC			

INTERFERENCE SEARCH					
Class	Subclass	Date	Examine		